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Supporting information for article:

Thermal stability of the layered modification of Cu0.5ZrTe2 in the temperature range 25–900 °C

E. G. Shkvarina, A. A. Titov, A. S. Shkvarin, J. R. Plaisier, L. Gigli and A. N. Titov

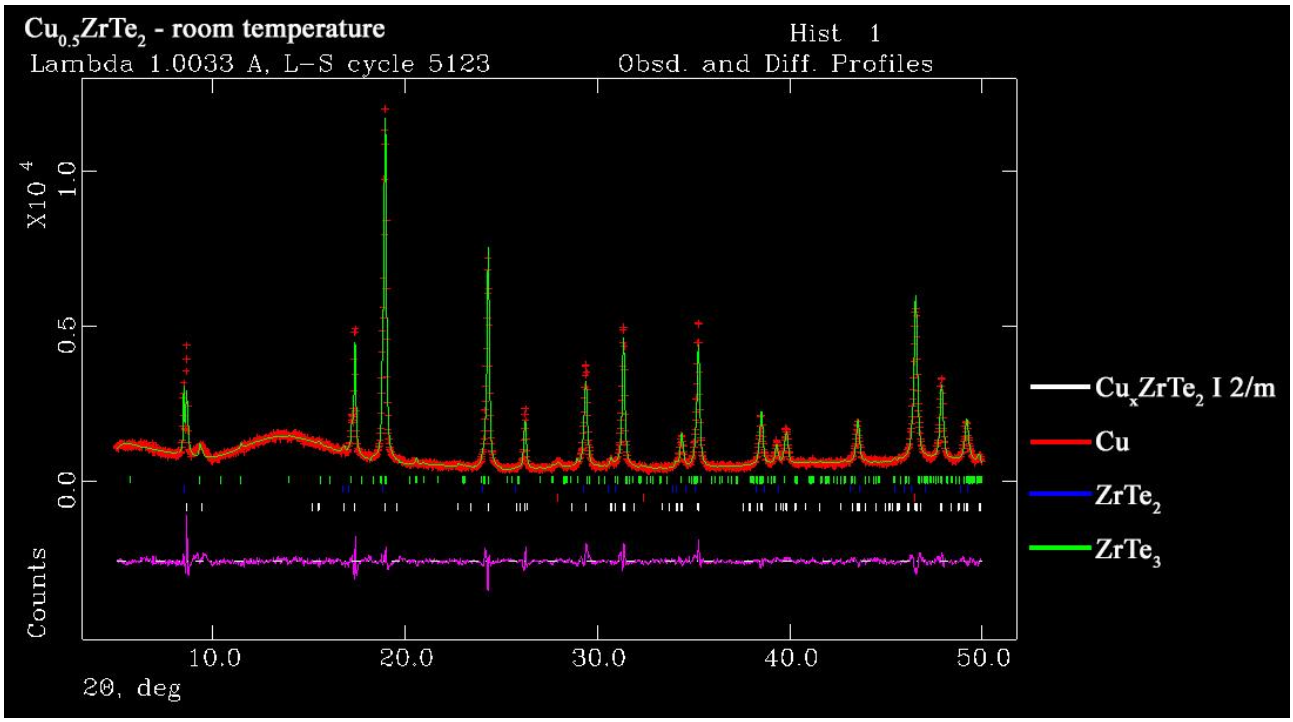

Fig. S1

The experimental (green line) and calculated (red cross) X-ray diffraction patterns for Cu0.5ZrTe2 (RT). As purple line are shown the difference curves between calculated and observed profiles. As colored tick are shown the contributions of the corresponding phases.

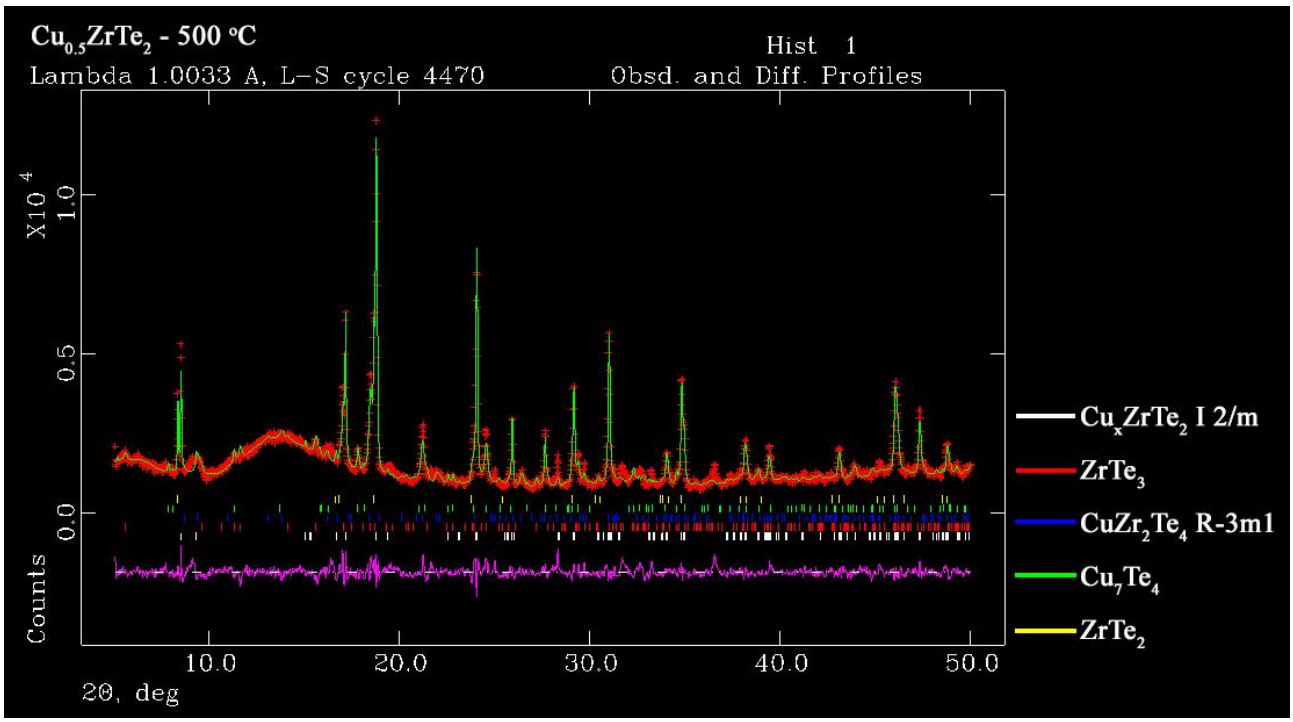

Fig. S2

The experimental (green line) and calculated (red cross) X-ray diffraction patterns for Cu0.5ZrTe2 (500 C). As purple line are shown the difference curves between calculated and observed profiles. As colored tick are shown the contributions of the corresponding phases.

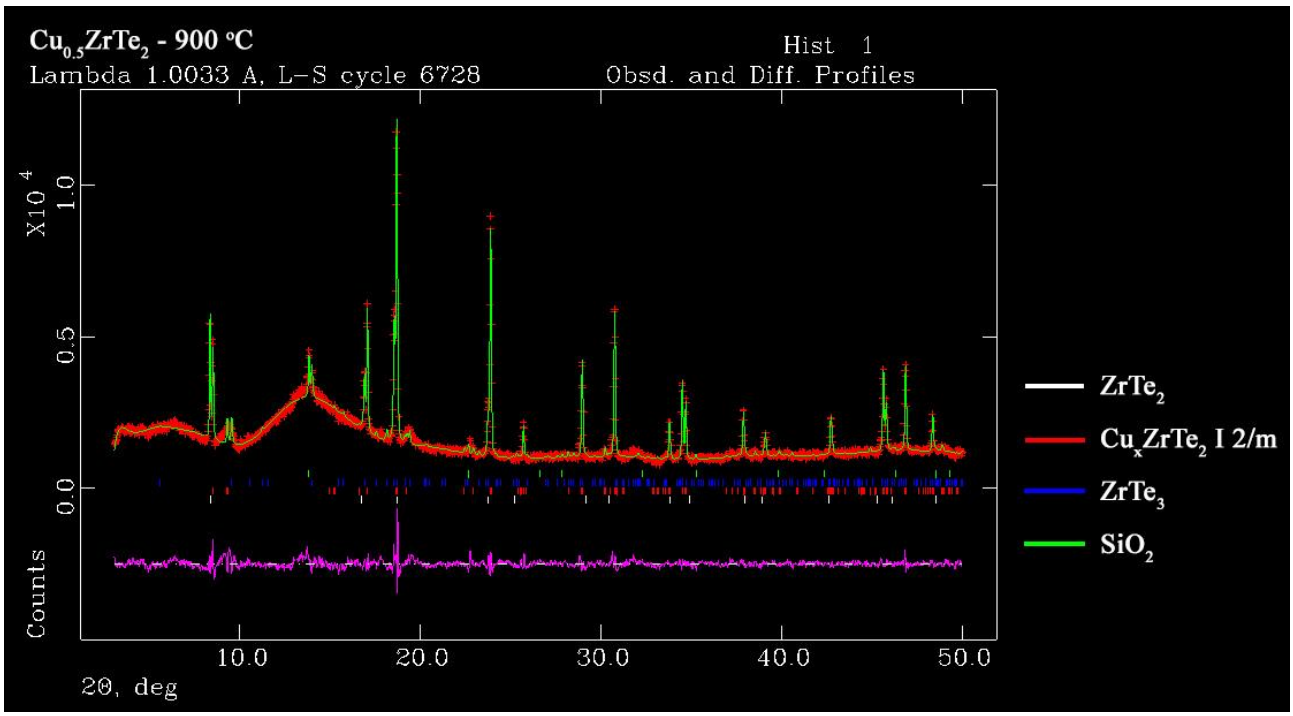

Fig. S3

The experimental (green line) and calculated (red cross) X-ray diffraction patterns for Cu0.5ZrTe2 (900 C). As purple line are shown the difference curves between calculated and observed profiles. As colored tick are shown the contributions of the corresponding phases.

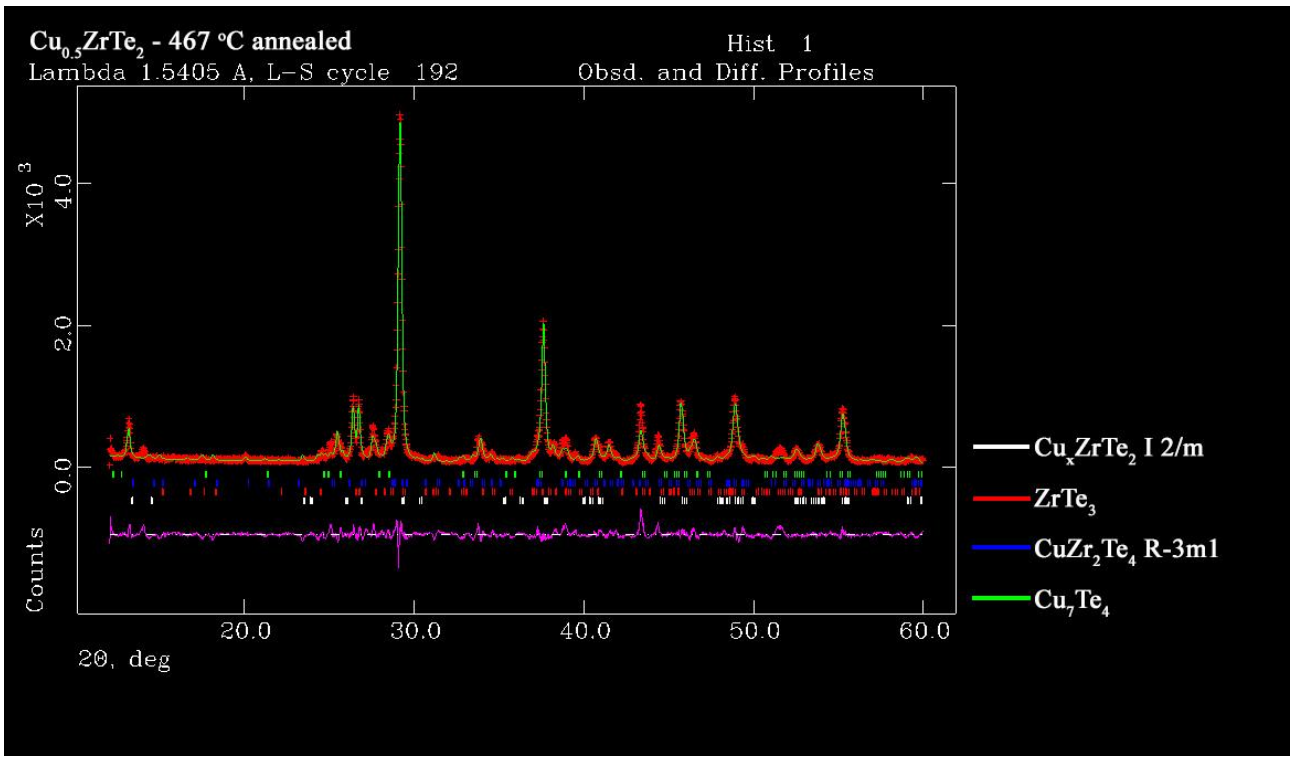

Fig. S4

The experimental (green line) and calculated (red cross) X-ray diffraction patterns for Cu0.5ZrTe2 (467 C annealed). As purple line are shown the difference curves between calculated and observed profiles. As colored tick are shown the contributions of the corresponding phases.